AFM Probe Specifications:
Coating
Reflective Aluminum
Additional Info
AFM probes of the 55AC series are designed for high speed AFM imaging.
The tetrahedral AFM tip is located precisely at the free end of the AFM cantilever. This allows the AFM tip to be positioned accurately over the area of interest on the sample surface.
The uncoated AFM tip offers a sharp AFM tip apex and chemical inertness. The back side aluminum coating significantly enhances the AFM cantilever reflectivity in air and vacuum. For operation in liquids we recommend using the 55AC-NG with a reflective gold coating.

AFM Tip:

Shape	Height	Setback	Radius	Half Cone Angle
Optimized Positioning	14 µm (12 - 16 µm)*	0 µm	< 7 nm	0° front, 35° back, <9° side

* typical values

AFM Cantilever:

Cantilever	Shape	Force Const.	Res. Freq.	Lenght	Width	Thickness
High frequency tapping mode AFM cantilever	Beam	85 N/m (35 - 215 N/m)*	1200 kHz (650 - 1850 kHz)*	65 µm (1 - 75µm)*	31 µm (29 - 33µm)*	2.9µm (2.4 - 3.4 µm)*

* typical values